

# APPENDIX A

<b>Notice of References Cited</b>	Application/Control No. 10/540,352	Applicant(s)/Patent Under Reexamination STRODER ET AL.	
	Examiner Mark L. Shevin	Art Unit 1793	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,578,798	05-1971	Lapple et al.	432/58
	B	US-			
	C	US-			
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*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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<b>Notice of References Cited</b>	Application/Control No. 10/540,073	Applicant(s)/Patent Under Reexamination ORTH ET AL	
	Examiner PREM C. SINGH	Art Unit 1797	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,716,856	01-1988	Beisswenger et al.	122/4D
*	B	US 5,560,762	10-1996	Bresser et al.	75/447
	C	US-			
	D	US-			
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	Examiner Mark L. Shevin		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,864,620	05-1975	Rammler, Roland	432/15
*	B	US-4,073,642	02-1978	Collin et al.	75/448
*	C	US-4,789,580	12-1988	Hirsch et al.	75/500
*	D	US-5,505,907	04-1996	Hiltunen et al.	422/146
*	E	US-5,527,379	06-1996	Hirsch et al.	75/436
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	N	WO 90/11824	10-1990	Finland	Engstrom	B01J 8/44
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	U	Y.T. Kim et al, Entrainment of solids in an internally circulating fluidized bed with draft tube. Chemical Engineering Journal, Vol. 66, (1997), p. 105-110.			
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	Examiner Mark L. Shevin	Art Unit 1793	Page 1 of 1

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*	A	US-2,607,666	08-1952	MARTIN HOMER Z	48/62R
*	B	US-3,578,798	05-1971	Lapple et al.	432/58
	C	US-			
	D	US-			
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	Examiner Mark L. Shevin		Art Unit 1793	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,505,907	04-1996	Hiltunen et al.	422/146
*	B	US-5,527,379	06-1996	Hirsch et al.	75/436
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Page 1 of 1

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<b>Notice of References Cited</b>	Application/Control No. 10/540,436	Applicant(s)/Patent Under Reexamination NUMBER, DIRK	
	Examiner Andrew M. Juettner	Art Unit 4124	Page 1 of 2

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*	A	US-2007/0137435	06-2007	Orth et al.	075/451
*	B	US-5,505,907	04-1996	Hiltunen et al.	122/4D
*	C	US-3,884,620	05-1975	Rammier, Roland	432/15
*	D	US-3,995,987	12-1976	MacAskill, Donald	432/15
*	E	US-2006/0278566	12-2006	Orth et al.	422/139
*	F	US-2006/0263292	11-2006	Hirsch et al.	423/625
*	G	US-3,565,408	02-1971	Lothar Reh; et. al.	423/625
*	H	US-4,091,085	05-1978	Reh et al.	432/15
*	I	US-4,555,388	11-1985	Hundebol, Soren	432/15
*	J	US-4,545,132	10-1985	Li et al.	432/16
*	K	US-5,437,850	08-1995	Kroehi et al.	423/555
*	L	US-5,560,762	10-1996	Bresser et al.	75/447
*	M	US-2,485,317	10-1949	ROETHELI BRUNO E	423/172

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	Examiner Andrew M. Juettner		Art Unit 4124	Page 2 of 2

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*	A	US-2006/0249100	11-2006	Freytag et al.	122/400
*	B	US-2006/0230879	10-2006	Stroder et al.	075/444
*	C	US-2006/0162500	07-2006	Nuber et al.	075/613
*	D	US-4,789,580	12-1988	Hirsch et al.	75/500
	E	US-			
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	Examiner TIMOTHY C. VANOY		Art Unit 1793	Page 1 of 1

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*	A	US-6,413,477 B1	07-2002	Govoni et al.	422/131
*	B	US-2,864,674	12-1958	KING WILLIAM R	23/314
*	C	US-2,714,126	07-1955	KEITH PERCIVAL C	585/535
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Examiner  
Gregory A. Wilson

Art Unit  
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*	A	US-4,817,563 A1	04-1989	Beisswenger et al.	122/4D
*	B	US-5,205,350 A	04-1993	Hirsch et al.	165/104.18
*	C	US-4,080,437 A1	03-1978	Reh et al.	423/625
*	D	US-4,402,754 A1	09-1983	Schmidt et al.	106/744
*	E	US-5,505,907 A	04-1996	Hiltunen et al.	422/146
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<b>Notice of References Cited</b>	Application/Control No. 10/540,376	Applicant(s)/Patent Under Reexamination NUBER ET AL.	
	Examiner Mark L. Shevin	Art Unit 1793	Page 1 of 1

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*	C	US-4,402,754	09-1983	Schmidt et al.	106/744
*	D	US-4,817,563	04-1989	Beisswenger et al.	122/4D
*	E	US-5,505,907	04-1996	Hiltunen et al.	422/146
*	F	US-2006/0231433	10-2006	Rufu et al.	206/308.1
*	G	US-2006/0230879	10-2006	Stroder et al.	075/444
*	H	US-2006/0230880	10-2006	Hirsch et al.	075/444
*	I	US-2006/0249100	11-2006	Freytag et al.	122/400
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	M	US-			

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	O	WO 90/11824	10-1990	Finland	Engstrom et al	B01J 8/44
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